

July 2010

## FDZ3N513ZT

## **Integrated NMOS and Schottky Diode**

## **Features**

- Monolithic NMOS and Schottky Diode
- Ultra-small form factor 1mm x 1mm WLCSP
- Max  $r_{DS(on)}$  = 462 m $\Omega$  at  $V_{GS}$  = 4.5 V,  $I_D$  = 0.3 A
- Max  $r_{DS(on)}$  = 520 m $\Omega$  at  $V_{GS}$  = 3.2 V,  $I_D$  = 0.3 A
- HBM ESD protection level > 2000V (Note3)
- RoHS Compliant

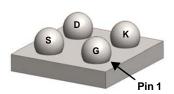
## **General Description**

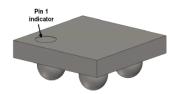
The FDZ3N513ZT is a monolithic NMOS/ Schottky combination (FETky) and is designed and wired to function as a discontinuous conduction mode (DCM) boost LED power train for mobile LED backlighting applications.

## **Application**

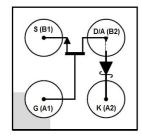
Boost Converter Power Train for single cell Li-ion LED backlighting







WL-CSP 3D Bumps Facing Down View



WL-CSP 1.0X1.0 Bumps Facing Up View

### **Absolute Maximum Ratings**

WL-CSP 3D Bumps Facing Up View

Symbol	Parameter	Ratings	Units	
V <sub>DS</sub>	NMOS Drain to Source Voltage	30	V	
$V_{GS}$	NMOS Gate to Source Voltage	-0.3/5.5	V	
P <sub>D</sub>	Power Dissipation @ T <sub>A</sub> = 25°C	1	W	
I <sub>D</sub>	Maximum Continuous NMOS Drain Current	1.1	Α	
$V_{RRM}$	Schottky Repetitive Peak Reverse Voltage	25	V	
Io	Schottky Average Forward Current		0.3	Α
T <sub>J</sub> , T <sub>STG</sub>	Operating Junction and Storage Temperature	-55/125	°C	
ESD	Electrostatic Discharge Protection CDM 2000			V

#### **Thermal Characteristics**

$R_{\theta JA}$	Thermal Resistance, Junction to Ambient - 1in², 2oz. Copper	(Note 1a)	100	°C/W
$R_{\theta JA}$	Thermal Resistance, Junction to Ambient - Minimum Pad	(Note 1b)	260	°C/W

## **Package Marking and Ordering Information**

Part Number	Device Marking	Package	Reel Size	Tape Width	Quantity
FDZ3N513ZT	Z3	WL-CSP 1.0X1.0	7"	8mm	5000 units

# Electrical Characteristics T<sub>J</sub> = 25 °C unless otherwise noted Perspeter Test Conditions

Symbol	Parameter	lest Conditions	Wiin	іур	wax	Units
Off Chara	octeristics					
BV <sub>DSS</sub>	Drain to Source Breakdown Voltage	$I_D = 250 \mu A, V_{GS} = 0 V$	30			V
$\frac{\Delta BV_{DSS}}{\Delta T_{J}}$	Breakdown Voltage Temperature Coefficient	$I_D$ = 250 $\mu$ A, referenced to 25 °C		47		mV/°C
I <sub>DSS</sub>	Zero Gate Voltage Drain Current	V <sub>DS</sub> = 24 V, V <sub>GS</sub> = 0 V			1	μΑ
I <sub>GSS</sub>	Gate to Source Leakage Current	$V_{GS} = +5 \text{ V/-}0.3 \text{ V}, V_{DS} = 0 \text{ V}$			±10	μΑ

### **On Characteristics**

V <sub>GS(th)</sub>	Gate to Source Threshold Voltage	$V_{GS} = V_{DS}$ , $I_D = 250 \mu A$	0.5	0.7	1.5	V
$\frac{\Delta V_{GS(th)}}{\Delta T_J}$	Gate to Source Threshold Voltage Temperature Coefficient	$I_D$ = 250 $\mu$ A, referenced to 25 °C		-1.6		mV/°C
-	r <sub>DS(on)</sub> Drain to Source On Resistance	$V_{GS} = 4.5 \text{ V}, I_D = 0.3 \text{ A}$		384	462	mΩ
<sup>r</sup> DS(on)		$V_{GS} = 3.2 \text{ V}, I_D = 0.3 \text{ A}$		410	520	11152
9 <sub>FS</sub>	Forward Transconductance	$V_{DS} = 5 \text{ V}, I_{D} = 0.3 \text{ A}$		0.5		S

## **Dynamic Characteristics**

C <sub>iss</sub>	Input Capacitance	45.77.77	45	85	pF
C <sub>oss</sub>	Output Capacitance	$V_{DS} = 15 \text{ V}, V_{GS} = 0 \text{ V},$ f = 1  MHz	45	85	pF
C <sub>rss</sub>	Reverse Transfer Capacitance	1 - 1 1011 12	10	25	pF
$R_g$	Gate Resistance		2.0		Ω

## **Switching Characteristics**

t <sub>d(on)</sub>	Turn-On Delay Time		3.1	10	ns
t <sub>r</sub>	Rise Time	V <sub>DD</sub> = 15 V, I <sub>D</sub> = 0.3 A	1.9	10	ns
t <sub>d(off)</sub>	Turn-Off Delay Time	$V_{GS} = 5 \text{ V}, R_{GEN} = 6 \Omega$	9.6	20	ns
t <sub>f</sub>	Fall Time		2.7	10	ns
$Q_{g}$	Total Gate Charge (V <sub>GS</sub> = 4.5 V)	V 45.V	1.0		nC
$Q_{gs}$	Gate to Source Gate Charge	$V_{DD} = 15 \text{ V}$ $I_{D} = 0.3 \text{ A}$	0.1		nC
$Q_{gd}$	Gate to Drain "Miller" Charge	ID = 0.0 A	0.3		nC

#### **Drain-Source Diode Characteristics**

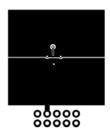
$V_{SD}$	Source to Drain Diode Forward Voltage	$V_{GS} = 0 \text{ V}, I_S = 0.3 \text{ A}$ (Note 2)		0.75	1.2	V
t <sub>rr</sub>	Reverse Recovery Time	1 - 0 3 A di/dt - 100 A/		16	29	ns
Q <sub>rr</sub>	Reverse Recovery Charge	F = 0.3 A, di/dt = 100 A/μs		6.0	10	nC

### **Schottky Diode Characteristics**

I_	Reverse Leakage	V <sub>R</sub> = 20 V	T <sub>J</sub> = 25 °C	15	30	μΑ
'R	Neverse Leakage	VR - 20 V	$T_J = 85  ^{\circ}C$	300		μΑ
V-	Forward Voltage	I <sub>F</sub> = 300 mA	T <sub>J</sub> = 25 °C	0.72	1.2	V
٧F	Forward Vollage	IF = 300 IIIA	$T_J = 85  ^{\circ}\text{C}$	0.74		V

#### Notes

<sup>1.</sup> R<sub>0JA</sub> is determined with the device mounted on a 1 in<sup>2</sup> oz. copper pad on a 1.5 x 1.5 in. board of FR-4 material. R<sub>0JC</sub> is guaranteed by design while R<sub>0JA</sub> is determined by the user's board design.



a. 100 °C/W when mounted on a 1 in<sup>2</sup> pad of 2 oz copper.



 b. 260 °C/W when mounted on a minimum pad of 2 oz copper.

- 2. Pulse Test: Pulse Width < 300  $\mu s,$  Duty cycle < 2.0%.
- 3. The diode connected between the gate and source serves only as protection ESD. No gate overvoltage rating is implied.

## Typical Characteristics T<sub>J</sub> = 25°C unless otherwise noted

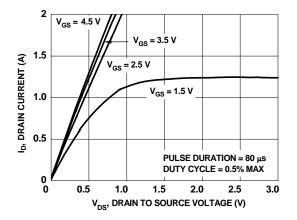


Figure 1. On Region Characteristics

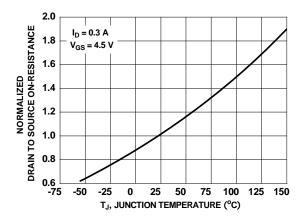


Figure 3. Normalized On Resistance vs Junction Temperature

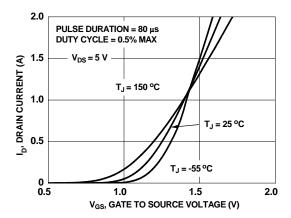


Figure 5. Transfer Characteristics

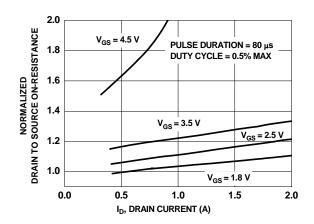


Figure 2. Normalized On-Resistance vs Drain Current and Gate Voltage

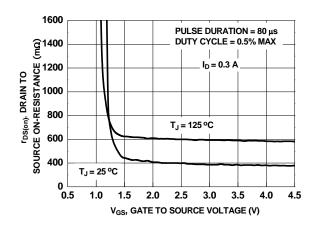


Figure 4. On-Resistance vs Gate to Source Voltage

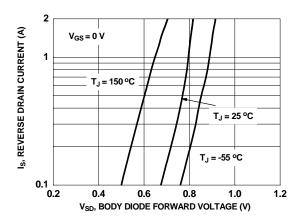


Figure 6. Source to Drain Diode Forward Voltage vs Source Current

## Typical Characteristics T<sub>J</sub> = 25°C unless otherwise noted

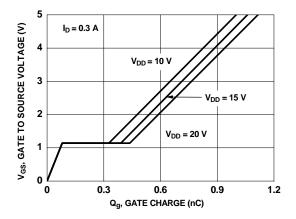


Figure 7. Gate Charge Characteristics

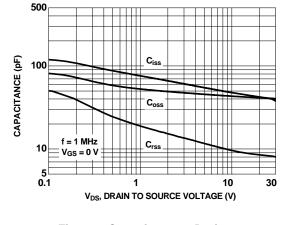


Figure 8. Capacitance vs Drain to Source Voltage

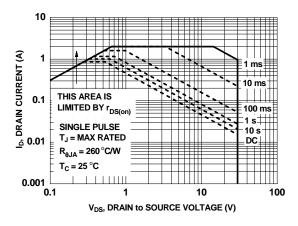


Figure 9. Forward Bias Safe Operating Area

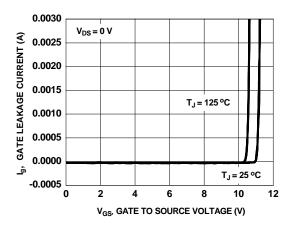


Figure 10. Gate Leakage Current vs Gate to Source Voltage

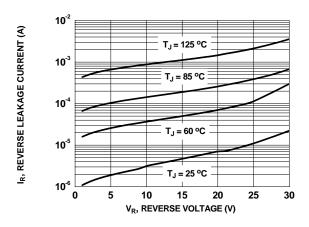


Figure 11. Schottky Diode Reverse Current

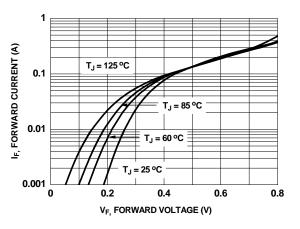


Figure 12. Schottky Diode Forward Voltage

## **Typical Characteristics** $T_J = 25$ °C unless otherwise noted

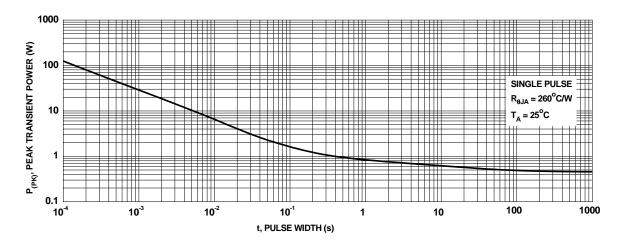


Figure 13. Single Pulse Maximum Power Dissipation

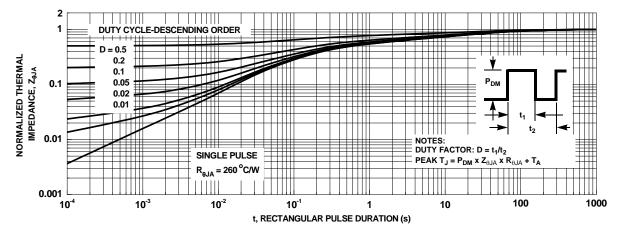
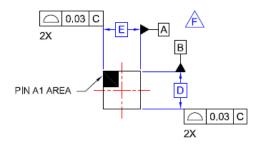
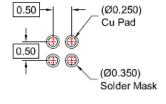


Figure 14. Junction-to-Ambient Transient Thermal Response Curve

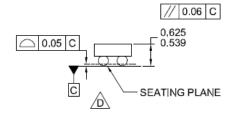
## **Dimensional Outline and Pad Layout**



TOP VIEW

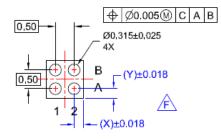


## RECOMMENDED LAND PATTERN (NSMD PAD TYPE)





SIDE VIEWS



**BOTTOM VIEW** 

## NOTES:

- A. NO JEDEC REGISTRATION APPLIES.
- B. DIMENSIONS ARE IN MILLIMETERS.
- C. DIMENSIONS AND TOLERANCES PER ASME Y14.5M, 1994.
- D. DATUM C IS DEFINED BY THE SPHERICAL CROWNS OF THE BALLS.
- E. PACKAGE NOMINAL HEIGHT IS 582 MICRONS ±43 MICRONS (539-625 MICRONS).

FOR DIMENSIONS D, E, X, AND Y SEE PRODUCT DATASHEET.

## **Product Specific Dimensions**

Product	D	E	Х	Y
FDZ3N513ZTUCX	1.000 +/-0.030	1.000 +/-0.030	0.018	0.018





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